

<b>Notic of R ferences Cited</b>	Application/Control No. 10/040,797	Applicant(s)/Patent Under Reexamination GOLDFINE ET AL.	
	Examiner Jeffrey R. West	Art Unit 2857	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,394,084	02-1995	Snyder	324/225
*	C	US-5,223,796	06-1993	Waldman et al.	324/687
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	JP-56151538-A	11-1981	JP	Isobe et al.	B29D27/00
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Zaretsky et al., "Continuum Properties from Interdigital Electrode Dielectrometry", IEEE Transactions on Electrical Insulation, Vol. 23, No. 6. December 1988.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.